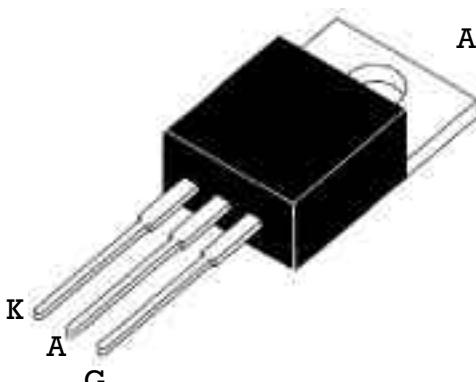


SENSITIVE GATE SCR

TO220-AB 	On-State Current 8 Amp	Gate Trigger Current < 200 μ A
	Off-State Voltage 200 V ÷ 600 V	
<p>These series of Silicon Controlled Rectifier use a high performance PNPN technology.</p> <p>These parts are intended for general purpose applications where high gate sensitivity is required using surface mount technology.</p>		

Absolute Maximum Ratings, according to IEC publication No. 134

SYMBOL	PARAMETER	CONDITIONS	Min.	Max.	Unit
$I_{T(RMS)}$	On-state Current	180° Conduction Angle, $T_c = 110^\circ C$		8	A
$I_{T(AV)}$	Average On-state Current	Half Cycle, $\alpha = 180^\circ$, $T_c = 110^\circ C$		5	A
I_{TSM}	Non-repetitive On-State Current	Half Cycle, 60 Hz		73	A
I_{TSM}	Non-repetitive On-State Current	Half Cycle, 50 Hz		70	A
I^{2t}	Fusing Current	$t_p = 10ms$, Half Cycle		24.5	A^2s
V_{GRM}	Peak Reverse Gate Voltage	$I_{GR} = 10 \mu A$		8	V
I_{GM}	Peak Gate Current	20 μs max.		4	A
P_{GM}	Peak Gate Dissipation	20 μs max.		5	W
$P_{G(AV)}$	Gate Dissipation	20ms max.		1	W
T_j	Operating Temperature		-40	+125	$^\circ C$
T_{stg}	Storage Temperature		-40	+150	$^\circ C$
T_{sld}	Soldering Temperature	10s max.		260	$^\circ C$

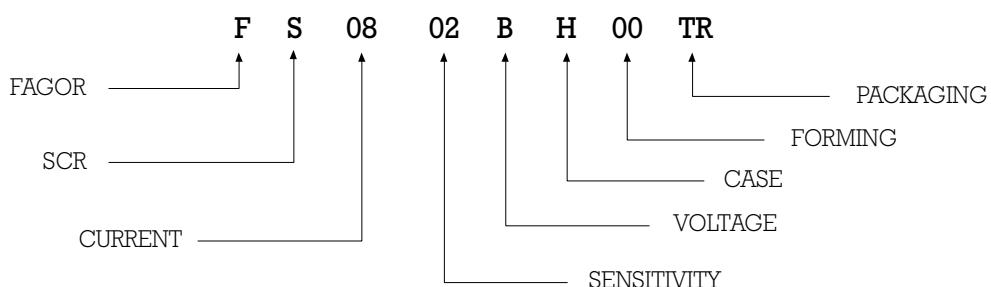
SYMBOL	PARAMETER	CONDITIONS	VOLTAGE			Unit
			B	D	M	
V_{DRM} V_{RRM}	Repetitive Peak Off State Voltage	$R_{GK} = 1 K$	200	400	600	V

SENSITIVE GATE SCR

Electrical Characteristics

SYMBOL	PARAMETER	CONDITIONS		SENSITIVITY	Unit
			02		
I_{GT}	Gate Trigger Current	$V_D = 12 \text{ V}_{DC}$, $R_L = 140 \Omega$, $T_j = 25^\circ\text{C}$	MAX	200	μA
I_{DRM} / I_{RRM}	Off-State Leakage Current	$V_D = V_{DRM}$, $R_{GK} = 220 \Omega$, $T_j = 125^\circ\text{C}$ $V_R = V_{RRM}$, $T_j = 25^\circ\text{C}$	MAX MAX	1 5	mA μA
V_{TM}	On-state Voltage	at $I_T = 16 \text{ Amp}$, $t_p = 380 \mu\text{s}$, $T_j = 25^\circ\text{C}$	MAX	1.6	V
V_{GT}	Gate Trigger Voltage	$V_D = 12 \text{ V}_{DC}$, $R_L = 140 \Omega$, $T_j = 25^\circ\text{C}$	MAX	0.8	V
V_{GD}	Gate Non Trigger Voltage	$V_D = V_{DRM}$, $R_L = 3.3\text{K}$, $R_{GK} = 220 \Omega$, $T_j = 125^\circ\text{C}$	MIN	0.1	V
I_H	Holding Current	$I_T = 50 \text{ mA}$, $R_{GK} = 1\text{K}$, $T_j = 25^\circ\text{C}$	MAX	5	mA
I_L	Latching Current	$I_G = 1 \text{ mA}$, $R_{GK} = 1 \text{ K}$	MAX	6	mA
dv/dt	Critical Rate of Voltage Rise	$V_D = 0.67 \times V_{DRM}$, $R_{GK} = 220 \Omega$, $T_j = 125^\circ\text{C}$	MIN	5	V/ μs
di/dt	Critical Rate of Current Rise	$I_G = 2 \times I_{GT}$, $T_r = 100 \text{ ns}$, $F = 60 \text{ Hz}$, $T_j = 125^\circ\text{C}$	MIN	50	A/ μs
$R_{th(j-c)}$	Thermal Resistance Junction-Case for DC			20	$^\circ\text{C}/\text{W}$
$R_{th(j-a)}$	Thermal Resistance Junction-Amb for DC			60	$^\circ\text{C}/\text{W}$
V_{t0}	Threshold Voltage	$T_j = 125^\circ\text{C}$	MAX	0.85	V
R_d	Dynamic resistance	$T_j = 125^\circ\text{C}$	MAX	46	m

PART NUMBER INFORMATION



SENSITIVE GATE SCR

Fig. 1: Maximum average power dissipation versus average on-state current.

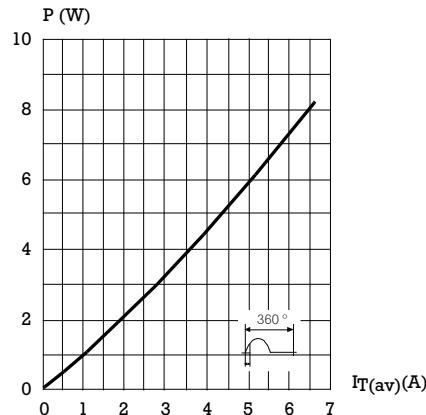


Fig. 3: Relative variation of thermal impedance junction to case versus pulse duration.

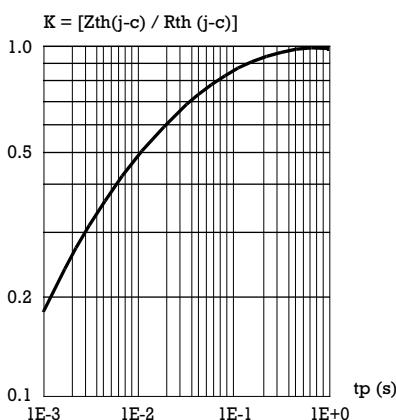


Fig. 5: Non repetitive surge peak on-state current versus number of cycles.

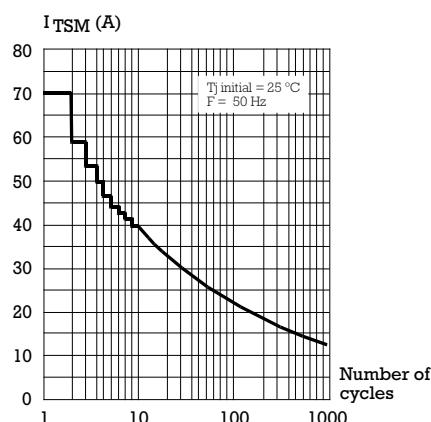


Fig. 2: Average and D.C. on-state current versus case temperature.

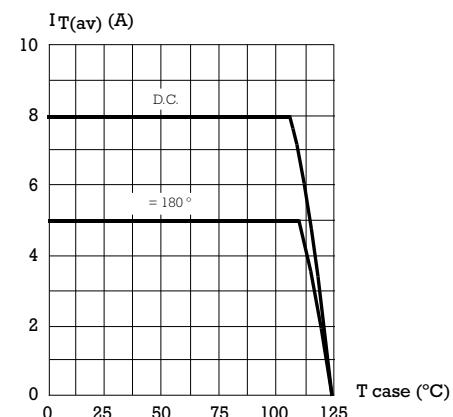


Fig. 4: Relative variation of gate trigger current, holding and latching current versus junction temperature.

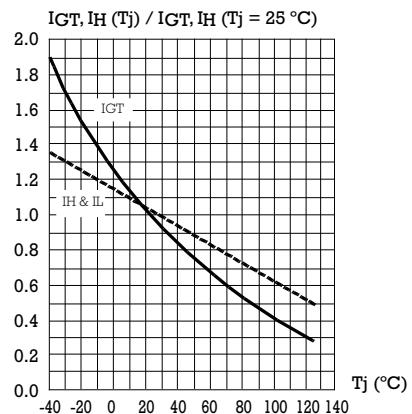
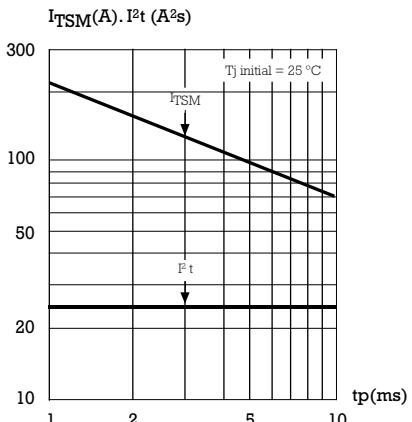
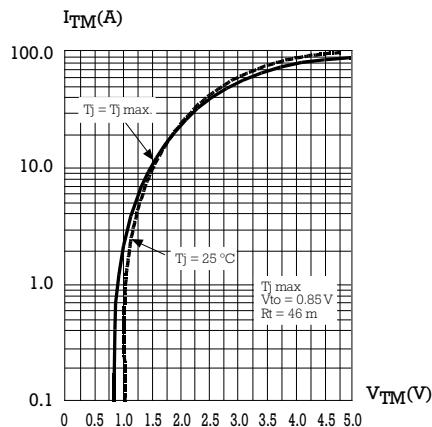


Fig. 6: Non repetitive surge peak on-state current for a sinusoidal pulse with width: tp < 10 ms, and corresponding value of I²t.



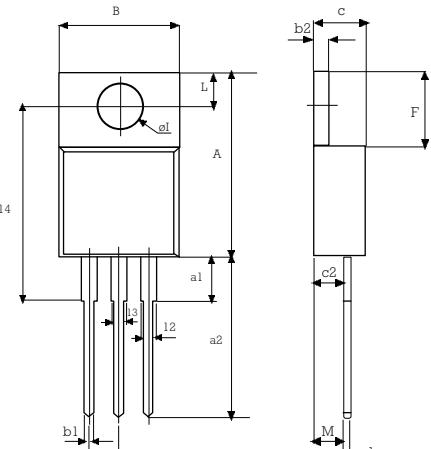
SENSITIVE GATE SCR

Fig. 7: On-state characteristics (maximum values).



PACKAGE MECHANICAL DATA

TO-220AB



REF.	DIMENSIONS		
	Milimeters		
	Min.	Nominal	Max.
A	15.20		15.90
a ₁		3.75	
a ₂	13.00		14.00
B	10.00		10.40
b ₁	0.61		0.88
b ₂	1.23		1.32
C	4.40		4.60
c ₁	0.49		0.70
c ₂	2.40		2.72
e	2.40		2.70
F	6.20		6.60
I	3.75		3.85
I ₄	15.80	16.40	16.80
L	2.65		2.95
I ₂	1.14		1.70
I ₃	1.14		1.70
M		2.60	